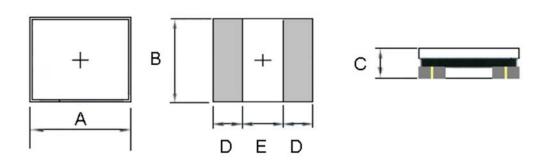


FEATRLRES

- This specification applies Low Profile Power Inductors.
- 100% Lead(Pb) & Halogen-Free and RoHS compliant.

CONFIGRLRATIONS & DIMENSIONS (unit in mm)



Туре	Α	В	С	D	E
HNRH252012	2.5 -0.1/+0.2	2.0 -0.1/+0.2	1.2max.	0.85 ref.	0.80 ref.

ELECTRICAL CHARACTERISTICS

Part Number	Inductance (uH)	Tolerance (%)	Test Frequency (Hz)	DCR (Ω) ±20%	I sat (A)typ.	I sat (A)max.	I rms (A)typ.	I rms (A)max.
HNRH252012-R47Y	0.47	±30%	0.1V/1M	0.028	4.00	3.60	3.70	3.35
HNRH252012-R68M	0.68	±20%	0.1V/1M	0.036	3.00	2.70	3.30	3.00
HNRH252012-1R0Y	1.0	±30%	0.1V/1M	0.049	2.70	2.45	2.60	2.30
HNRH252012-1R5Y	1.5	±30%	0.1V/1M	0.063	2.30	2.05	2.20	1.95
HNRH252012-2R2M	2.2	±20%	0.1V/1M	0.080	2.15	1.95	1.85	1.65
HNRH252012-3R3M	3.3	±20%	0.1V/1M	0.120	1.70	1.50	1.45	1.30
HNRH252012-4R7M	4.7	±20%	0.1V/1M	0.176	1.50	1.35	1.20	1.05
HNRH252012-6R8M	6.8	±20%	0.1V/1M	0.250	1.15	1.00	1.00	0.90
HNRH252012-100M	10	±20%	0.1V/1M	0.410	0.85	0.75	0.75	0.65
HNRH252012-150M	15	±20%	0.1V/1M	0.540	0.63	0.56	0.60	0.54
HNRH252012-220M	22	±20%	0.1V/1M	0.850	0.56	0.50	0.50	0.45

Note:

Isat : Based on inductance change $(\triangle L/L0 : \leq -30\%)$ @ ambient temp. 25°C

Irms : Based on temperature rise $(\triangle T : 40^{\circ}C \text{ typ.})$



1

0.75

0.5

0.25

0

2

1.6

1.2

0.8

0.4

0

3.5

2.8

0

0.5

Inductance(uH)

0

1

Inductance(uH)

2 3 DCcurrent(A)

1.5 DCcurrent(A)

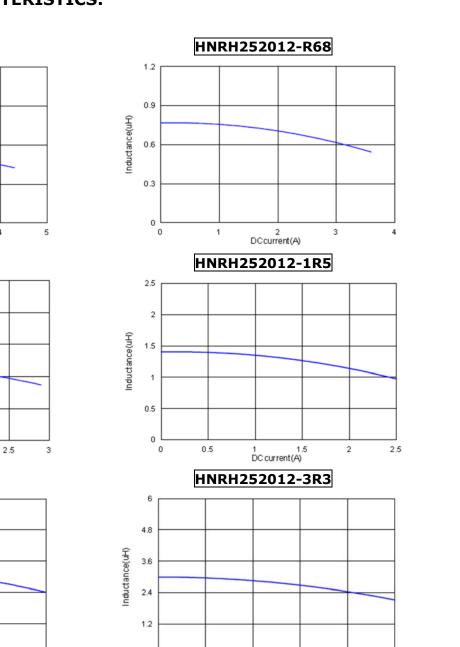
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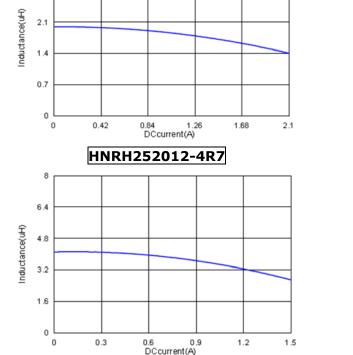
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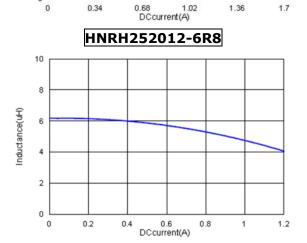
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HNRH252012-R47





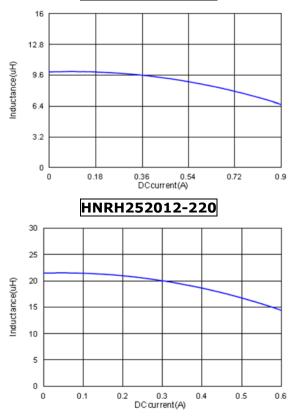


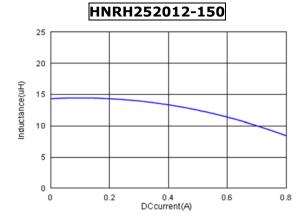
HSIA TECHNOLOGY CO.LTD. TEL:886-2-2999-6691 FAX: 2999-6692 Website:www.hsia.com.tw

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HNRH252012-100





Reliability and Test Condition

ltem	Performance	Test Condition				
Operating temperature	-40~+125°C (Including self - temperature rise)					
Storage temperature	110~+40℃,50~60%RH (Product with taping) 240~+125℃ (on board)					
Electrical Performance Test						
Inductance	Bofor to standard clostring observatoriation list	HP4284A,CH11025,CH3302,CH1320,CH1320S LCR Meter.				
DCR		CH16502,Agilent33420A Micro-Ohm Meter.				
Saturation Current (Isat)	Approximately_L30%	Saturation DC Current (Isat) will cause L0 to drop				
Heat Rated Current (Irms)	Approximately △T40℃	Heat Rated Current (Irms) will cause the coil temperature rise $\triangle T(\degree C)$. 1.Applied the allowed DC current 2.Temperature measured by digital surface thermometer				
Reliability Test						
		Preconditioning: Run through IR reflow for 2 times.(IPC/JEDEC J-STD-020DClassification Reflow Profiles)				
Life Test		C (Including self - temperature rise) C: (Including self - temperature rise) VC_50~60%RH (Product with taping) ISC (on board) andard electrical characteristics list. V_L30% V_L430% Saturation DC Current (Isat) will cause L0 to drop △L(%) Y △T40°C Preconditioning: Run through IR reflow for 2 times.(IPC/JEDEC J-STD-020DClassification Reflow Profiles) Temperature : 125±2° (Inductor) Applied current : rated current Duration : 1000±12hrs Wo damage. within±10% of initial value exceed the specification value. ±15% of initial value and shall not				
	Appearance : No damage.	Duration : 1000±12hrs				
Load Humidity	Inductance : within±10% of initial value Q : Shall not exceed the specification value. RDC : within ±15% of initial value and shall not exceed the specification value	J-STD-020DClassification Reflow Profiles Humidity : 85±2 * R.H,				



Moisture Resistance		020 Prof 1. B for 4 2. F hou 3. F hou 2.5h 4. K 10 t	DClassific files Baked at50 4 hrs. Raise tem Irs, cool do Raise tem Irs, cool do hrs,keep a	cation 0° for peratu- pown to peratu-	Reflow r 25hrs, n ure to 65 25° in ure to 65 25° in c for 2 hrs 0-100%RHz, measu	the assure $\pm 2^{\circ} C = 9$ 2.5 hrs. $\pm 2^{\circ} C = 9$ as then k H for 15 irre at	ed at room te 90-100%RH 90-100%RH keep at -10℃ simin and vib	es.(IPC/JEDEC mperature afte in 2.5hrs, and in 2.5hrs, and c for 3 hrs rate at the freq	r placing I keep 3 I keep 3
Thermal shock		020 Refl Con Step Step Step	DClassific flow Profile ndition for p1 : -40±2 p2 : 25±2 p3 : 125±2 mber of cy	cation es 1 cycl 2°C 30 °C ≦0 2°C 30 2°C 30	e D±5min 0.5min 0±5min 500		ow for 2 time r placing for	es.(IPC/JEDEC	C J-STD-
Vibration		Equ Tota Tes	uipment : al Amplitue	Vibra de:1.5	tion chec 2mm±10	ker %	Hz for 20 min , 12 cycles e		
Bending		Shall be mounted on a FR4 substrate of the following dimensions: >=0805 inch(2012mm):40x100x1.2mm <0805 inch(2012mm):40x100x0.8mm Bending depth: >=0805 inch(2012mm):1.2mm <0805 inch(2012mm):0.8mm duration of 10 sec.							
Shock	Appearance : No damage. Impedance : within±15% of initial value Inductance : within±10% of initial value Q : Shall not exceed the specification value. RDC : within ±15% of initial value and shall not exceed the specification value	s	Type val (g SMD 5		Norr duratio (ms 11	n (D) s)	Wave form Half-sine Half-sine	Velocity change (Vi)ft/sec 11.3 11.3	
Solder ability	More than 95% of the terminal electrode should be covered with solder。	Preheat: 150°C,60sec.₀ Solder: Sn96.5% Ag3% Cu0.5% Temperature: 245±5°C ∘ Flux for lead free: Rosin. 9.5% ∘ Dip time: 4±1sec ∘ Depth: completely cover the termination						-	
Resistance to Soldering Heat			pth: comple Temperatur 260 ±5 (solder te	re(°C)	1	Ter ramp and e	ation mperature s/immersion mersion rate n/s ±6 mm/s	Number of heat cycles	
Terminal Strength	Appearance : No damage. Impedance : within±15% of initial value Inductance : within±10% of initial value Q : Shall not exceed the specification value. RDC : within ±15% of initial value and shall not exceed the specification value e	Preconditioning: Run through IR reflow for 2 times.(IPC/JEDEC J-STD- 020DClassification Reflow Profiles With the component mounted on a PCB with the device to be tested, apply a force(>0805:1kg , <=0805:0.5kg)to the side of a device being tested. This force shall be applied for 60 +1 seconds. Also the force shall be applied gradually as not to apply a shock to the component being tested.							

Note : When there are questions concerning measurement result : measurement shall be made after 48 ± 2 hours of recovery under the standard condition.